N-Channel Enhancement Mode MOSFET

Description

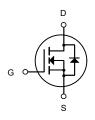
The NVMFS024N06CT1G uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

DFN5X6-8L

General Features

 $V_{DS} = 60V I_{D} = 30 A$

 $R_{DS(ON)} < 25m\Omega$ @ $V_{GS}=10V$



N-Channel MOSFET

Application

Battery protection

Load switch

Uninterruptible power supply

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
NVMFS024N06CT1G	DFN5X6-8L	HXY MOSFET	5000

Absolute Maximum Ratings (T_c=25[°]Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	60	V
VGS	Gate-Source Voltage	V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	30	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	15	А
IDM	Pulsed Drain Current ²	46	А
EAS	Single Pulse Avalanche Energy ³	25.5	mJ
IAS	Avalanche Current	22.6	А
P _D @T _C =25°C	Total Power Dissipation⁴	34.7	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-ambient ¹	62	°C/W
ReJC	R _θ JC Thermal Resistance Junction-Case ¹		°C/W

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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			V	
△BV _{DSS} /△T	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.063		V/°C	
В	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =15A		20	25	m0	
$R_{DS(ON)}$	Static Dialii-Source On-Resistance	V _{GS} =4.5V , I _D =10A		24	20	mΩ	
V _{GS(th)}	Gate Threshold Voltage	\/ -\/ -250\	1.2		2.5	V	
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		-5.24		mV/°C	
	Drain Sauras Laskaga Current	V _{DS} =48V , V _{GS} =0V , T _J =25°C			1	uA	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =55°C			5		
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =15A		17		S	
R_g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		3.2		Ω	
Q_g	Total Gate Charge (4.5V)			12.6			
Q_{gs}	Gate-Source Charge	V _{DS} =48V , V _{GS} =4.5V , I _D =12A		3.2		nC	
Q_{gd}	Gate-Drain Charge			6.3			
T _{d(on)}	Turn-On Delay Time			8			
Tr	Rise Time	V_{DD} =30V , V_{GS} =10V , R_{G} =3.3 Ω ,		14.2		20	
T _{d(off)}	Turn-Off Delay Time	I _D =10A		24.4		ns	
T _f	Fall Time			4.6			
C _{iss}	Input Capacitance			1378			
C _{oss}	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		86		pF	
C _{rss}	Reverse Transfer Capacitance			64			

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,5}	V =V =0V Force Current			30	Α
I _{SM}	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			46	Α
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V

Note:

- 1. The data tested by surface mounted on a 1 inch -4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V, L=0.1mH, I_{AS} =22.6A
- 4.The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

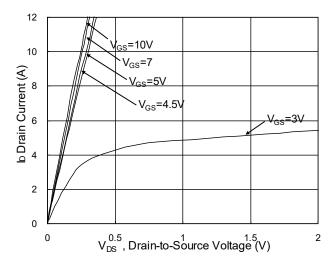


Fig.1 Typical Output Characteristics

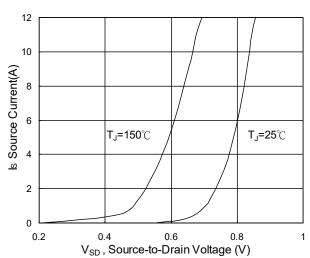


Fig.3 Forward Characteristics of Reverse

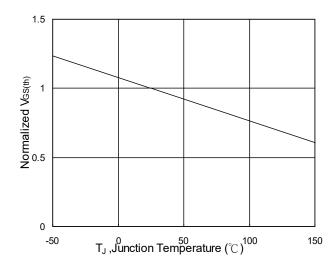


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

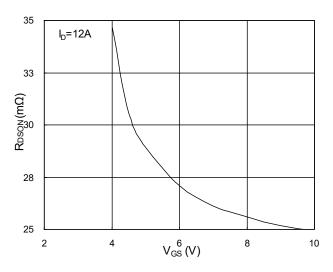


Fig.2 On-Resistance v.s Gate-Source

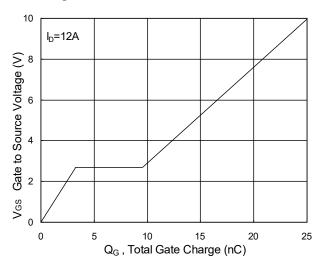


Fig.4 Gate-Charge Characteristics

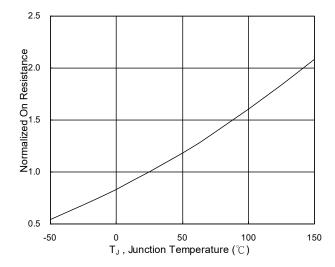
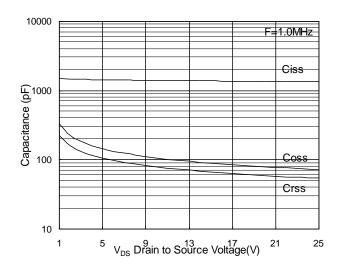


Fig.6 Normalized R_{DSON} v.s T_J



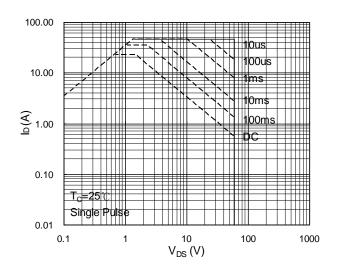


Fig.7 Capacitance

Fig.8 Safe Operating Area

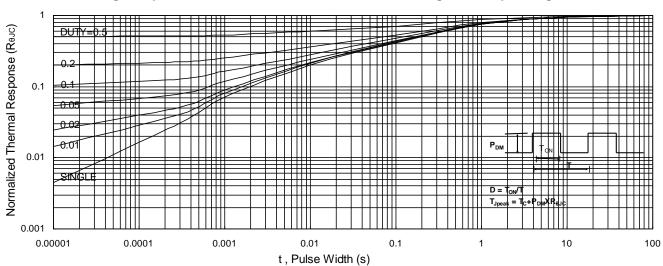


Fig.9 Normalized Maximum Transient Thermal Impedance

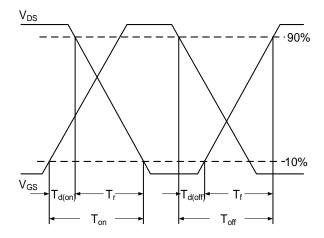


Fig.10 Switching Time Waveform

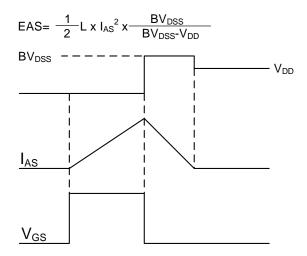
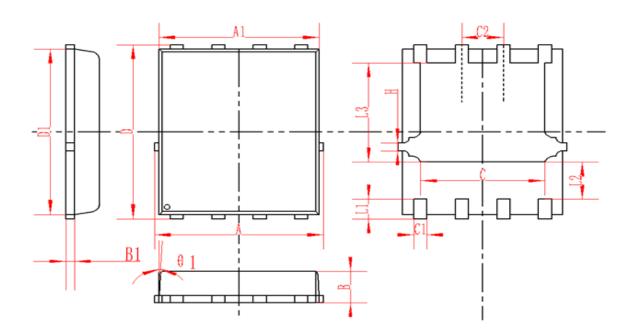


Fig.11 Unclamped Inductive Waveform

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DFN5X6-8L Package Information



SYMBOL	MM			INCH			
STIVIDOL	MIN	NOM	MAX	MIN	NOM	MAX	
А	4.95	5	5.05	0.195	0.197	0.199	
A1	4.82	4.9	4.98	0.190	0.193	0.196	
D	5.98	6	6.02	0.235	0.236	0.237	
D1	5.67	5.75	5.83	0.223	0.226	0.230	
В	0.9	0.95	1	0.035	0.037	0.039	
B1	0.254REF			0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159	
C1	0.35	0.4	0.45	0.014	0.016	0.018	
C2	1.27TYP			0.5TYP			
θ1	8°	10°	12°	8°	10°	12°	
L1	0.63	0.64	0.65	0.025	0.025	0.026	
L2	1.2	1.3	1.4	0.047	0.051	0.055	
L3	3.415	3.42	3.425	0.134	0.135	0.135	
Η	0.24	0.25	0.26	0.009	0.010	0.010	

NVMFS024N06CT1G

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